NAME

CUTEST ccf threaded - CUTEst tool to evaluate constraint functions values.

SYNOPSIS

```
CALL CUTEST ccf threaded( status, n, m, X, C, thread )
```

For real rather than double precision arguments, instead

```
CALL CUTEST_ccf_threaded_s( ... )
```

and for quadruple precision arguments, when available,

```
CALL CUTEST_ccf_threaded_q( ... )
```

DESCRIPTION

The CUTEST_ccf_threaded subroutine evaluates the values of the constraint functions of the problem decoded from a SIF file by the script *sifdecoder* at the point X.

The problem under consideration is to minimize or maximize an objective function f(x) over all $x \in \mathbb{R}^n$ subject to general equations $c_i(x) = 0$, $(i \in 1, ..., m_E)$, general inequalities $c_i^l \le c_i(x) \le c_i^u$, $(i \in m_E + 1, ..., m)$, and simple bounds $x^l \le x \le x^u$. The objective function is group-partially separable and all constraint functions are partially separable.

ARGUMENTS

The arguments of CUTEST_ccf_threaded are as follows

status [out] - integer

the outputr status: 0 for a successful call, 1 for an array allocation/deallocation error, 2 for an array bound error, 3 for an evaluation error, 4 for an out-of-range thread,

n [in] - integer

the number of variables for the problem,

m [in] - integer

the total number of general constraints,

X [in] - real/double precision

an array which gives the current estimate of the solution of the problem,

C [out] - real/double precision

an array which gives the values of the general constraint functions evaluated at X. The i-th component of C will contain the value of $c_i(x)$.

thread [in] - integer

thread chosen for the evaluation; threads are numbered from 1 to the value threads set when calling CUTEST csetup threaded.

AUTHORS

J.M. Fowkes, N.I.M. Gould, A. Montoison and D. Orban

SEE ALSO

CUTEst: a Constrained and Unconstrained Testing Environment with safe threads, N.I.M. Gould, D. Orban and Ph.L. Toint, Computational Optimization and Applications **60**:3, pp.545-557, 2014.

CUTEr (and SifDec): A Constrained and Unconstrained Testing Environment, revisited, N.I.M. Gould, D. Orban and Ph.L. Toint, ACM TOMS, **29**:4, pp.373-394, 2003.

CUTE: Constrained and Unconstrained Testing Environment, I. Bongartz, A.R. Conn, N.I.M. Gould and Ph.L. Toint, ACM TOMS, **21**:1, pp.123-160, 1995.

sifdecoder(1)